

Notice of References Cited

Application/Control No.

10/580,648

Applicant(s)/Patent Under
Reexamination
TANAKA ET AL.

Examiner

ANDREW IWAMAYE

Art Unit

3774

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	K	US-			
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FOREIGN PATENT DOCUMENTS

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*	N	JP 2002-347107	04-2002	Japan	Shimomura et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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